

# Search Notes



Application/Control No.

10/727,363

Examiner

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Applicant(s)/Patent under Reexamination

BOTICH ET AL.

Art Unit

3767

## SEARCHED

Class	Subclass	Date	Examiner
604	162	7/24/2006	mlh.
	164.01		
	164.07		
	164.08		
	164.09		
	165.01		
	171		
	187		
	192		
	198		
	263		
	264		
	272		
	533		

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
EAST text search	7/24/2006	mlh.